2025-02-14(금), 10:55-12:40
좌장: 추후업데이트 예정

F. Silicon and Group-IV Devices and Integration Technology 분과

[FH2-F] Process-Device Characterization

FH2-F-1 10:55-11:10	**Low-Temperature Deuterium Annealing for Improved Immunity against Hot-Carrier Injection in HKMG MOSFETs** Ju-Won Yeon, Hyo-Jun Park, Tae-Hyun Kil, Moon-Kwon Lee, Eui-Cheol Yun, Min-Woo Kim, Su-Jin Jeon, Dol Sohn, A-Young Kim, Sang-Min Kang, Da-Eun Bang, and Jun-Young Park Chungbuk National University
FH2-F-2 11:10-11:25	**Comprehensive Understanding of Polarization Mechanism and Low Operating Voltage by Hf0.5Zr0.5O2 Thickness Scaling on Ge Channel** Jai-Youn Jeong[1,2], Kyul Ko[1], Changhwan Shin[2], and Jae-Hoon Han[1] [1]Center for Opto-electronic Materials and Devices, KIST,[2]Device and Circuit Laboratory, Korea University
FH2-F-3 11:25-11:40	**Accurate Modeling of NCFET-Based Ring Oscillators** Jung Su Kim and Changhwan Shin School of Electrical Engineering, Korea University
FH2-F-4 11:40-11:55	**Improvement of Current Drivability through Current Limiter towards Bulk DTMOS with Low-Power High-Performance Operation Versatility** Yeji Lim and Seongjae Cho Department of Electronic and Electrical Engineering, Ewha Womans University
FH2-F-5 11:55-12:10	**Multi-Vt Engineering for Logic Devices Using Rare Earth Oxide-Based Dipole-First Approach with Various Interfacial Layer Formation** Sang Kuk Han[1], Hyun Jin Lim[1], Ki Sub Kim[1], Hyo Jin Ahn[1], Yeh Been Im[1], Won Jae Choi[2], Young Seo Na[2], and Changhwan Choi[1,2] [1]Division of Materials Science and Engineering, Hanyang University, [2]Department of Semiconductor Engineering, Hanyang University
FH2-F-6 12:10-12:25	**Effects of Thermal Annealing Conditions on IGZO-Based MFMIS Ferroelectric TFTs** Hyeonjung Park[1] and Changhwan Shin[2] [1]Department of Electrical and Computer Engineering, Sungkyunkwan University, [2]School of Electrical Engineering, Korea University

FH2-F-7 12:25-12:40	Atomic Layer Deposition for High-Mobility and Reliable ITZO Thin Film Transistors Hyeonjin Lee[1], Hyeonho Gu[2], Minho Park[2], Yongwoo Lee[2], and Jimin Kwon[1,2] [1]Graduate School of Semiconductor Materials and Devices Engineering, UNIST, [2]Department of Electrical Engineering, UNIST